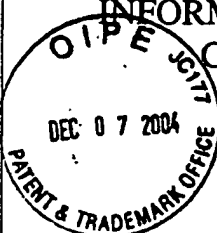
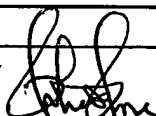


SHEET 1 OF 1

INFORMATION DISCLOSURE CITATION IN AN APPLICATION (PTO-1449)				ATTY. DOCKET NO. 005917 USA/FET/FET		SERIAL NO. 09/998,372	
				APPLICANT Young Joseph PAIK			
				FILING DATE November 30, 2001		GROUP 3723	
U.S. PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE	
CB	5,901,313	05/04/99	Wolf et al.			09/02/97	
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EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
CB	WO 99/59200	11/18/99	WIPO			X	
CB	WO 01/52319	07/19/01	WIPO			X	
OTHER ART (including Author, Title, Date, Pertinent Pages, Etc.)							
CB	Williams, Randy, Dadi Gudmundsson, Kevin Monahan, Raman Nurani, Meryl Stoller and J. George Shanthikumar. October 1999. "Optimized Sample Planning for Wafer Defect Inspection," <i>Semiconductor Manufacturing Conference Proceedings, 1999 IEEE International Symposium on Santa Clara, CA</i> . Piscataway, NJ. pp. 43 - 46.						
CB	23 July 2003. Invitation to Pay Additional Fees and Communication Relating to the Results of the Partial International Search for PCT/US02/19116.						
CB	01 August 2003. Written Opinion for PCT/US01/27406.						
CB	20 August 2003. Written Opinion for PCT/US01/22833.						
EXAMINER				DATE CONSIDERED			
				02/23/05			

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

<p align="center">INFORMATION DISCLOSURE CITATION IN AN APPLICATION (PTO-1449)</p> 	<p>ATTY. DOCKET NO. 005917 USA/FET/FET</p>	<p>SERIAL NO. 09/998,372</p>
	<p>APPLICANT Young Joseph PAIK</p>	
	<p>FILING DATE November 30, 2001</p>	<p>GROUP 3723</p>
<p align="center">OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)</p>		
<p><u>83</u></p>	<p>October 12, 2004. International Preliminary Examination Report for PCT Serial No. PCT/US02/19061.</p>	
<p>EXAMINER</p> 	<p>DATE CONSIDERED 02/23/05</p>	

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

(PTO-1449)

SERIAL NO.
09/998,372

FILING DATE
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**GROUP
3723**

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EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
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<i>BR</i>	6,735,492 B2	05/11/04	Conrad et al.			07/19/02
EXAMINER	<i>[Signature]</i>		DATE CONSIDERED	<i>02/23/05</i>		

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<p style="text-align: center;">INFORMATION DISCLOSURE CITATION IN AN APPLICATION (PTO-1449)</p> <p><i>Stamp: OIPE JC177 DEC 07 2004 PATENT & TRADEMARK OFFICE</i></p>	ATTY. DOCKET NO. 005917 USA/FET/FET	SERIAL NO. 09/998,372
	APPLICANT Young Joseph PAIK	
	FILING DATE November 30, 2001	GROUP 3723
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)		
<i>QR</i>	September 15, 2004. Office Action for U.S. Serial No. 10/632,107, filed August 1, 2003.	
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	October 1, 2004. International Preliminary Examination Report for PCT Serial No. PCT/US03/23964.	
↓	October 6, 2004. Office Action for U.S. Serial No. 10/759,108, filed January 20, 2004.	
<i>QR</i>	November 17, 2004. Written Opinion for PCT Serial No. PCT/US01/27407.	
EXAMINER <i>[Signature]</i>	DATE CONSIDERED <i>02/23/05</i>	

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